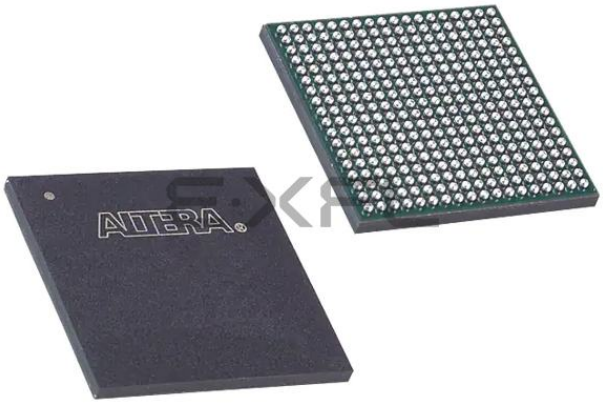

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Details	
Product Status	Active
Number of LABs/CLBs	1840
Number of Logic Elements/Cells	29440
Total RAM Bits	1105920
Number of I/O	150
Number of Gates	-
Voltage - Supply	1.16V ~ 1.24V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	324-LBGA
Supplier Device Package	324-FBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep4cgx30cf19c6

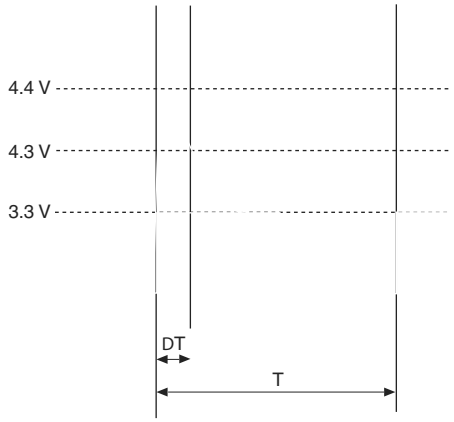
☞ A DC signal is equivalent to 100% duty cycle. For example, a signal that overshoots to 4.3 V can only be at 4.3 V for 65% over the lifetime of the device; for a device lifetime of 10 years, this amounts to 65/10ths of a year.

Table 1–2. Maximum Allowed Overshoot During Transitions over a 10-Year Time Frame for Cyclone IV Devices

Symbol	Parameter	Condition (V)	Overshoot Duration as % of High Time	Unit
V_i	AC Input Voltage	V_I = 4.20	100	%
		V_I = 4.25	98	%
		V_I = 4.30	65	%
		V_I = 4.35	43	%
		V_I = 4.40	29	%
		V_I = 4.45	20	%
		V_I = 4.50	13	%
		V_I = 4.55	9	%
		V_I = 4.60	6	%

Figure 1–1 shows the methodology to determine the overshoot duration. The overshoot voltage is shown in red and is present on the input pin of the Cyclone IV device at over 4.3 V but below 4.4 V. From Table 1–2, for an overshoot of 4.3 V, the percentage of high time for the overshoot can be as high as 65% over a 10-year period. Percentage of high time is calculated as ([delta T]/T) × 100. This 10-year period assumes that the device is always turned on with 100% I/O toggle rate and 50% duty cycle signal. For lower I/O toggle rates and situations in which the device is in an idle state, lifetimes are increased.

Figure 1–1. Cyclone IV Devices Overshoot Duration



Recommended Operating Conditions

This section lists the functional operation limits for AC and DC parameters for Cyclone IV devices. Table 1–3 and Table 1–4 list the steady-state voltage and current values expected from Cyclone IV E and Cyclone IV GX devices. All supplies must be strictly monotonic without plateaus.

Table 1–3. Recommended Operating Conditions for Cyclone IV E Devices (1), (2) (Part 1 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{CCINT} (3)	Supply voltage for internal logic, 1.2-V operation	—	1.15	1.2	1.25	V
	Supply voltage for internal logic, 1.0-V operation	—	0.97	1.0	1.03	V
V_{CCIO} (3), (4)	Supply voltage for output buffers, 3.3-V operation	—	3.135	3.3	3.465	V
	Supply voltage for output buffers, 3.0-V operation	—	2.85	3	3.15	V
	Supply voltage for output buffers, 2.5-V operation	—	2.375	2.5	2.625	V
	Supply voltage for output buffers, 1.8-V operation	—	1.71	1.8	1.89	V
	Supply voltage for output buffers, 1.5-V operation	—	1.425	1.5	1.575	V
	Supply voltage for output buffers, 1.2-V operation	—	1.14	1.2	1.26	V
V_{CCA} (3)	Supply (analog) voltage for PLL regulator	—	2.375	2.5	2.625	V
V_{CCD_PLL} (3)	Supply (digital) voltage for PLL, 1.2-V operation	—	1.15	1.2	1.25	V
	Supply (digital) voltage for PLL, 1.0-V operation	—	0.97	1.0	1.03	V
V_I	Input voltage	—	–0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	—	85	°C
		For industrial use	–40	—	100	°C
		For extended temperature	–40	—	125	°C
		For automotive use	–40	—	125	°C
t_{RAMP}	Power supply ramp time	Standard power-on reset (POR) (5)	50 µs	—	50 ms	—
		Fast POR (6)	50 µs	—	3 ms	—

Table 1–3. Recommended Operating Conditions for Cyclone IV E Devices (1), (2) (Part 2 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
I_{Diode}	Magnitude of DC current across PCI-clamp diode when enable	—	—	—	10	mA

Notes to Table 1–3:

(1) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades.

(2) V_{CCIO} for all I/O banks must be powered up during device operation. All VCCA pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.

(3) V_{CC} must rise monotonically.

(4) V_{CCIO} powers all input buffers.

(5) The POR time for Standard POR ranges between 50 and 200 ms. Each individual power supply must reach the recommended operating range within 50 ms.

(6) The POR time for Fast POR ranges between 3 and 9 ms. Each individual power supply must reach the recommended operating range within 3 ms.

Table 1–4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 1 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{CCINT} (3)	Core voltage, PCIe hard IP block, and transceiver PCS power supply	—	1.16	1.2	1.24	V
V_{CCA} (1), (3)	PLL analog power supply	—	2.375	2.5	2.625	V
V_{CCD_PLL} (2)	PLL digital power supply	—	1.16	1.2	1.24	V
V_{CCIO} (3), (4)	I/O banks power supply for 3.3-V operation	—	3.135	3.3	3.465	V
	I/O banks power supply for 3.0-V operation	—	2.85	3	3.15	V
	I/O banks power supply for 2.5-V operation	—	2.375	2.5	2.625	V
	I/O banks power supply for 1.8-V operation	—	1.71	1.8	1.89	V
	I/O banks power supply for 1.5-V operation	—	1.425	1.5	1.575	V
	I/O banks power supply for 1.2-V operation	—	1.14	1.2	1.26	V
V_{CC_CLKIN} (3), (5), (6)	Differential clock input pins power supply for 3.3-V operation	—	3.135	3.3	3.465	V
	Differential clock input pins power supply for 3.0-V operation	—	2.85	3	3.15	V
	Differential clock input pins power supply for 2.5-V operation	—	2.375	2.5	2.625	V
	Differential clock input pins power supply for 1.8-V operation	—	1.71	1.8	1.89	V
	Differential clock input pins power supply for 1.5-V operation	—	1.425	1.5	1.575	V
	Differential clock input pins power supply for 1.2-V operation	—	1.14	1.2	1.26	V
V_{CCH_GXB}	Transceiver output buffer power supply	—	2.375	2.5	2.625	V

Table 1–4. Recommended Operating Conditions for Cyclone IV GX Devices (Part 2 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{CCA_GXB}	Transceiver PMA and auxiliary power supply	—	2.375	2.5	2.625	V
V_{CCL_GXB}	Transceiver PMA and auxiliary power supply	—	1.16	1.2	1.24	V
V_I	DC input voltage	—	–0.5	—	3.6	V
V_O	DC output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	—	85	°C
		For industrial use	–40	—	100	°C
t_{RAMP}	Power supply ramp time	Standard power-on reset (POR) *(7)*	50 µs	—	50 ms	—
		Fast POR *(8)*	50 µs	—	3 ms	—
I_{Diode}	Magnitude of DC current across PCI-clamp diode when enabled	—	—	—	10	mA

Notes to Table 1–4:

(1) All VCCA pins must be powered to 2.5 V (even when PLLs are not used) and must be powered up and powered down at the same time.

(2) You must connect V_{CCD_PLL} to V_{CCINT} through a decoupling capacitor and ferrite bead.

(3) Power supplies must rise monotonically.

(4) V_{CCIO} for all I/O banks must be powered up during device operation. Configurations pins are powered up by V_{CCIO} of I/O Banks 3, 8, and 9 where I/O Banks 3 and 9 only support V_{CCIO} of 1.5, 1.8, 2.5, 3.0, and 3.3 V. For fast passive parallel (FPP) configuration mode, the V_{CCIO} level of I/O Bank 8 must be powered up to 1.5, 1.8, 2.5, 3.0, and 3.3 V.

(5) You must set V_{CC_CLKIN} to 2.5 V if you use CLKIN as a high-speed serial interface (HSSI) refclk or as a DIFFCLK input.

(6) The CLKIN pins in I/O Banks 3B and 8B can support single-ended I/O standard when the pins are used to clock left PLLs in non-transceiver applications.

(7) The POR time for Standard POR ranges between 50 and 200 ms. V_{CCINT}, V_{CCA}, and V_{CCIO} of I/O Banks 3, 8, and 9 must reach the recommended operating range within 50 ms.

(8) The POR time for Fast POR ranges between 3 and 9 ms. V_{CCINT}, V_{CCA}, and V_{CCIO} of I/O Banks 3, 8, and 9 must reach the recommended operating range within 3 ms.

ESD Performance

This section lists the electrostatic discharge (ESD) voltages using the human body model (HBM) and charged device model (CDM) for Cyclone IV devices general purpose I/Os (GPIOs) and high-speed serial interface (HSSI) I/Os. Table 1–5 lists the ESD for Cyclone IV devices GPIOs and HSSI I/Os.

Table 1–5. ESD for Cyclone IV Devices GPIOs and HSSI I/Os

Symbol	Parameter	Passing Voltage	Unit
V_{ESDHBM}	ESD voltage using the HBM (GPIOs) *(1)*	± 2000	V
	ESD using the HBM (HSSI I/Os) *(2)*	± 1000	V
V_{ESDCDM}	ESD using the CDM (GPIOs)	± 500	V
	ESD using the CDM (HSSI I/Os) *(2)*	± 250	V

Notes to Table 1–5:

(1) The passing voltage for EP4CGX15 and EP4CGX30 row I/Os is ±1000V.

(2) This value is applicable only to Cyclone IV GX devices.

Table 1–7. Bus Hold Parameter for Cyclone IV Devices (Part 2 of 2) (1)

Parameter	Condition	V_{CCIO} (V)												Unit
		1.2		1.5		1.8		2.5		3.0		3.3		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus hold trip point	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

Note to Table 1–7:

(1) Bus hold trip points are based on the calculated input voltages from the JEDEC standard.

OCT Specifications

Table 1–8 lists the variation of OCT without calibration across process, temperature, and voltage (PVT).

Table 1–8. Series OCT Without Calibration Specifications for Cyclone IV Devices

Description	V_{CCIO} (V)	Resistance Tolerance		Unit
		Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	
Series OCT without calibration	3.0	±30	±40	%
	2.5	±30	±40	%
	1.8	±40	±50	%
	1.5	±50	±50	%
	1.2	±50	±50	%

OCT calibration is automatically performed at device power-up for OCT-enabled I/Os.

Table 1–9 lists the OCT calibration accuracy at device power-up.

Table 1–9. Series OCT with Calibration at Device Power-Up Specifications for Cyclone IV Devices

Description	V_{CCIO} (V)	Calibration Accuracy		Unit
		Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	
Series OCT with calibration at device power-up	3.0	±10	±10	%
	2.5	±10	±10	%
	1.8	±10	±10	%
	1.5	±10	±10	%
	1.2	±10	±10	%

The OCT resistance may vary with the variation of temperature and voltage after calibration at device power-up. Use Table 1–10 and Equation 1–1 to determine the final OCT resistance considering the variations after calibration at device power-up. Table 1–10 lists the change percentage of the OCT resistance with voltage and temperature.

Table 1–10. OCT Variation After Calibration at Device Power-Up for Cyclone IV Devices

Nominal Voltage	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.262	–0.026
2.5	0.234	–0.039
1.8	0.219	–0.086
1.5	0.199	–0.136
1.2	0.161	–0.288

Equation 1–1. Final OCT Resistance *(1), (2), (3), (4), (5), (6)*

$$\Delta R_V = (V_2 - V_1) \times 1000 \times dR/dV \quad (7)$$

$$\Delta R_T = (T_2 - T_1) \times dR/dT \quad (8)$$

$$\text{For } \Delta R_x < 0;\ MF_x = 1/(|\Delta R_x|/100 + 1) \quad (9)$$

$$\text{For } \Delta R_x > 0;\ MF_x = \Delta R_x/100 + 1 \quad (10)$$

$$MF = MF_V \times MF_T \quad (11)$$

$$R_{final} = R_{initial} \times MF \quad (12)$$

Notes to Equation 1–1:

(1) T_2 is the final temperature.
(2) T_1 is the initial temperature.
(3) MF is multiplication factor.
(4) R_{final} is final resistance.
(5) $R_{initial}$ is initial resistance.
(6) Subscript $_x$ refers to both $_V$ and $_T$.
(7) ΔR_V is a variation of resistance with voltage.
(8) ΔR_T is a variation of resistance with temperature.
(9) dR/dT is the change percentage of resistance with temperature after calibration at device power-up.
(10) dR/dV is the change percentage of resistance with voltage after calibration at device power-up.
(11) V_2 is final voltage.
(12) V_1 is the initial voltage.

Example 1–1 shows how to calculate the change of 50-Ω I/O impedance from 25°C at 3.0 V to 85°C at 3.15 V.

Example 1–1. Impedance Change

$\Delta R_V = (3.15 – 3) \times 1000 \times –0.026 = –3.83$

$\Delta R_T = (85 – 25) \times 0.262 = 15.72$

Because ΔR_V is negative,

$MF_V = 1 / (3.83/100 + 1) = 0.963$

Because ΔR_T is positive,

$MF_T = 15.72/100 + 1 = 1.157$

$MF = 0.963 \times 1.157 = 1.114$

$R_{final} = 50 \times 1.114 = 55.71\ \Omega$

Pin Capacitance

Table 1–11 lists the pin capacitance for Cyclone IV devices.

Table 1–11. Pin Capacitance for Cyclone IV Devices *(1)*

Symbol	Parameter	Typical – Quad Flat Pack (QFP)	Typical – Quad Flat No Leads (QFN)	Typical – Ball-Grid Array (BGA)	Unit
C_{IOTB}	Input capacitance on top and bottom I/O pins	7	7	6	pF
C_{IOLR}	Input capacitance on right I/O pins	7	7	5	pF
C_{LVDSLR}	Input capacitance on right I/O pins with dedicated LVDS output	8	8	7	pF
C_{VREFLR} *(2)*	Input capacitance on right dual-purpose VREF pin when used as V_{REF} or user I/O pin	21	21	21	pF
C_{VREFTB} *(2)*	Input capacitance on top and bottom dual-purpose VREF pin when used as V_{REF} or user I/O pin	23 *(3)*	23	23	pF
C_{CLKTB}	Input capacitance on top and bottom dedicated clock input pins	7	7	6	pF
C_{CLKLR}	Input capacitance on right dedicated clock input pins	6	6	5	pF

Notes to Table 1–11:

(1) The pin capacitance applies to FBGA, UBGA, and MBGA packages.

(2) When you use the VREF pin as a regular input or output, you can expect a reduced performance of toggle rate and t_{CO} because of higher pin capacitance.

(3) C_{VREFTB} for the EP4CE22 device is 30 pF.

Internal Weak Pull-Up and Weak Pull-Down Resistor

Table 1–12 lists the weak pull-up and pull-down resistor values for Cyclone IV devices.

Table 1–12. Internal Weak Pull-Up and Weak Pull-Down Resistor Values for Cyclone IV Devices *(1)*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{_PU}$	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option	V_{CCIO} = 3.3 V ± 5% *(2), (3)*	7	25	41	kΩ
		V_{CCIO} = 3.0 V ± 5% *(2), (3)*	7	28	47	kΩ
		V_{CCIO} = 2.5 V ± 5% *(2), (3)*	8	35	61	kΩ
		V_{CCIO} = 1.8 V ± 5% *(2), (3)*	10	57	108	kΩ
		V_{CCIO} = 1.5 V ± 5% *(2), (3)*	13	82	163	kΩ
		V_{CCIO} = 1.2 V ± 5% *(2), (3)*	19	143	351	kΩ
$R_{_PD}$	Value of the I/O pin pull-down resistor before and during configuration	V_{CCIO} = 3.3 V ± 5% *(4)*	6	19	30	kΩ
		V_{CCIO} = 3.0 V ± 5% *(4)*	6	22	36	kΩ
		V_{CCIO} = 2.5 V ± 5% *(4)*	6	25	43	kΩ
		V_{CCIO} = 1.8 V ± 5% *(4)*	7	35	71	kΩ
		V_{CCIO} = 1.5 V ± 5% *(4)*	8	50	112	kΩ

Notes to Table 1–12:

(1) All I/O pins have an option to enable weak pull-up except the configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG TCK.

(2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.

(3) $R_{_PU} = (V_{CCIO} – V_I)/I_{R_PU}$
Minimum condition: –40°C; $V_{CCIO} = V_{CC}$ + 5%, $V_I = V_{CC}$ + 5% – 50 mV;
Typical condition: 25°C; $V_{CCIO} = V_{CC}$, V_I = 0 V;
Maximum condition: 100°C; $V_{CCIO} = V_{CC}$ – 5%, V_I = 0 V; in which V_I refers to the input voltage at the I/O pin.

(4) $R_{_PD} = V_I/I_{R_PD}$
Minimum condition: –40°C; $V_{CCIO} = V_{CC}$ + 5%, V_I = 50 mV;
Typical condition: 25°C; $V_{CCIO} = V_{CC}$, $V_I = V_{CC}$ – 5%;
Maximum condition: 100°C; $V_{CCIO} = V_{CC}$ – 5%, $V_I = V_{CC}$ – 5%; in which V_I refers to the input voltage at the I/O pin.

Hot-Socketing

Table 1–13 lists the hot-socketing specifications for Cyclone IV devices.

Table 1–13. Hot-Socketing Specifications for Cyclone IV Devices

Symbol	Parameter	Maximum
$I_{IOPIN(DC)}$	DC current per I/O pin	300 µA
$I_{IOPIN(AC)}$	AC current per I/O pin	8 mA *(1)*
$I_{XCVRTX(DC)}$	DC current per transceiver TX pin	100 mA
$I_{XCVRRX(DC)}$	DC current per transceiver RX pin	50 mA

Note to Table 1–13:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, |IIOPIN| = C dv/dt, in which C is the I/O pin capacitance and dv/dt is the slew rate.

☞ During hot-socketing, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20 pF.

Table 1–20. Differential I/O Standard Specifications for Cyclone IV Devices (1) (Part 2 of 2)

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)		V_{ICM} (V) (2)			V_{OD} (mV) (3)			V_{OS} (V) (3)		
	Min	Typ	Max	Min	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
LVDS (Column I/Os)	2.375	2.5	2.625	100	—	0.05	$D_{MAX} \leq$ 500 Mbps	1.80	247	—	600	1.125	1.25	1.375
						0.55	500 Mbps $\leq D_{MAX} \leq$ 700 Mbps	1.80						
						1.05	D_{MAX} > 700 Mbps	1.55						
BLVDS (Row I/Os) (4)	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—
BLVDS (Column I/Os) (4)	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—
mini-LVDS (Row I/Os) (5)	2.375	2.5	2.625	—	—	—	—	—	300	—	600	1.0	1.2	1.4
mini-LVDS (Column I/Os) (5)	2.375	2.5	2.625	—	—	—	—	—	300	—	600	1.0	1.2	1.4
RSDS® (Row I/Os) (5)	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.5
RSDS (Column I/Os) (5)	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.5
PPDS (Row I/Os) (5)	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.4
PPDS (Column I/Os) (5)	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.4

Notes to Table 1–20:

(1) For an explanation of terms used in Table 1–20, refer to "Glossary" on page 1–37.

(2) V_{IN} range: 0 V $\leq V_{IN} \leq$ 1.85 V.

(3) R_L range: 90 $\leq R_L \leq$ 110 Ω.

(4) There are no fixed V_{IN}, V_{OD}, and V_{OS} specifications for BLVDS. They depend on the system topology.

(5) The Mini-LVDS, RSDS, and PPDS standards are only supported at the output pins.

(6) The LVPECL I/O standard is only supported on dedicated clock input pins. This I/O standard is not supported for output pins.

Transceiver Performance Specifications

Table 1–21 lists the Cyclone IV GX transceiver specifications.

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 1 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Reference Clock											
Supported I/O Standards	1.2 V PCML, 1.5 V PCML, 3.3 V PCML, Differential LVPECL, LVDS, HCSL										
Input frequency from REFCLK input pins	—	50	—	156.25	50	—	156.25	50	—	156.25	MHz
Spread-spectrum modulating clock frequency	Physical interface for PCI Express (PIPE) mode	30	—	33	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PIPE mode	—	0 to –0.5%	—	—	0 to –0.5%	—	—	0 to –0.5%	—	—
Peak-to-peak differential input voltage	—	0.1	—	1.6	0.1	—	1.6	0.1	—	1.6	V
V_{ICM} (AC coupled)	—	1100 ± 5%			1100 ± 5%			1100 ± 5%			mV
V_{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	250	—	550	mV
Transmitter REFCLK Phase Noise *(1)*	Frequency offset = 1 MHz – 8 MHZ	—	—	–123	—	—	–123	—	—	–123	dBc/Hz
Transmitter REFCLK Total Jitter *(1)*		—	—	42.3	—	—	42.3	—	—	42.3	ps
R_{ref}	—	—	2000 ± 1%	—	—	2000 ± 1%	—	—	2000 ± 1%	—	Ω
Transceiver Clock											
cal_blk_clk clock frequency	—	10	—	125	10	—	125	10	—	125	MHz
fixedclk clock frequency	PCIe Receiver Detect	—	125	—	—	125	—	—	125	—	MHz
reconfig_clk clock frequency	Dynamic reconfiguration clock frequency	2.5/ 37.5 *(2)*	—	50	2.5/ 37.5 *(2)*	—	50	2.5/ 37.5 *(2)*	—	50	MHz
Delta time between reconfig_clk	—	—	—	2	—	—	2	—	—	2	ms
Transceiver block minimum power-down pulse width	—	—	1	—	—	1	—	—	1	—	µs

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 2 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Receiver											
Supported I/O Standards	1.4 V PCML, 1.5 V PCML, 2.5 V PCML, LVPECL, LVDS										
Data rate (F324 and smaller package) *(15)*	—	600	—	2500	600	—	2500	600	—	2500	Mbps
Data rate (F484 and larger package) *(15)*	—	600	—	3125	600	—	3125	600	—	2500	Mbps
Absolute V_{MAX} for a receiver pin *(3)*	—	—	—	1.6	—	—	1.6	—	—	1.6	V
Operational V_{MAX} for a receiver pin	—	—	—	1.5	—	—	1.5	—	—	1.5	V
Absolute V_{MIN} for a receiver pin	—	–0.4	—	—	–0.4	—	—	–0.4	—	—	V
Peak-to-peak differential input voltage V_{ID} (diff p-p)	V_{ICM} = 0.82 V setting, Data Rate = 600 Mbps to 3.125 Gbps	0.1	—	2.7	0.1	—	2.7	0.1	—	2.7	V
V_{ICM}	V_{ICM} = 0.82 V setting	—	820 ± 10%	—	—	820 ± 10%	—	—	820 ± 10%	—	mV
Differential on-chip termination resistors	100–Ω setting	—	100	—	—	100	—	—	100	—	Ω
	150–Ω setting	—	150	—	—	150	—	—	150	—	Ω
Differential and common mode return loss	PIPE, Serial Rapid I/O SR, SATA, CPRI LV, SDI, XAUI	Compliant									—
Programmable ppm detector *(4)*	—	± 62.5, 100, 125, 200, 250, 300									ppm
Clock data recovery (CDR) ppm tolerance (without spread-spectrum clocking enabled)	—	—	—	±300 *(5)*, ±350 *(6)*, *(7)*	—	—	±300 *(5)*, ±350 *(6)*, *(7)*	—	—	±300 *(5)*, ±350 *(6)*, *(7)*	ppm
CDR ppm tolerance (with synchronous spread-spectrum clocking enabled) *(8)*	—	—	—	350 to –5350 *(7)*, *(9)*	—	—	350 to –5350 *(7)*, *(9)*	—	—	350 to –5350 *(7)*, *(9)*	ppm
Run length	—	—	80	—	—	80	—	—	80	—	UI
Programmable equalization	No Equalization	—	—	1.5	—	—	1.5	—	—	1.5	dB
	Medium Low	—	—	4.5	—	—	4.5	—	—	4.5	dB
	Medium High	—	—	5.5	—	—	5.5	—	—	5.5	dB
	High	—	—	7	—	—	7	—	—	7	dB

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 3 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Signal detect/loss threshold	PIPE mode	65	—	175	65	—	175	65	—	175	mV
t_{LTR} *(10)*	—	—	—	75	—	—	75	—	—	75	µs
$t_{LTR-LTD_Manual}$ *(11)*	—	15	—	—	15	—	—	15	—	—	µs
t_{LTD} *(12)*	—	0	100	4000	0	100	4000	0	100	4000	ns
t_{LTD_Manual} *(13)*	—	—	—	4000	—	—	4000	—	—	4000	ns
t_{LTD_Auto} *(14)*	—	—	—	4000	—	—	4000	—	—	4000	ns
Receiver buffer and CDR offset cancellation time (per channel)	—	—	—	17000	—	—	17000	—	—	17000	reconfig_clk cycles
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	3	—	—	3	—	—	3	—	dB
	DC Gain Setting = 2	—	6	—	—	6	—	—	6	—	dB
Transmitter											
Supported I/O Standards	1.5 V PCML										
Data rate (F324 and smaller package)	—	600	—	2500	600	—	2500	600	—	2500	Mbps
Data rate (F484 and larger package)	—	600	—	3125	600	—	3125	600	—	2500	Mbps
V_{OCM}	0.65 V setting	—	650	—	—	650	—	—	650	—	mV
Differential on-chip termination resistors	100–Ω setting	—	100	—	—	100	—	—	100	—	Ω
	150–Ω setting	—	150	—	—	150	—	—	150	—	Ω
Differential and common mode return loss	PIPE, CPRI LV, Serial Rapid I/O SR, SDI, XAUI, SATA	Compliant									—
Rise time	—	50	—	200	50	—	200	50	—	200	ps
Fall time	—	50	—	200	50	—	200	50	—	200	ps
Intra-differential pair skew	—	—	—	15	—	—	15	—	—	15	ps
Intra-transceiver block skew	—	—	—	120	—	—	120	—	—	120	ps

Figure 1–2 shows the lock time parameters in manual mode.

LTD = lock-to-data. LTR = lock-to-reference.

Figure 1–2. Lock Time Parameters for Manual Mode

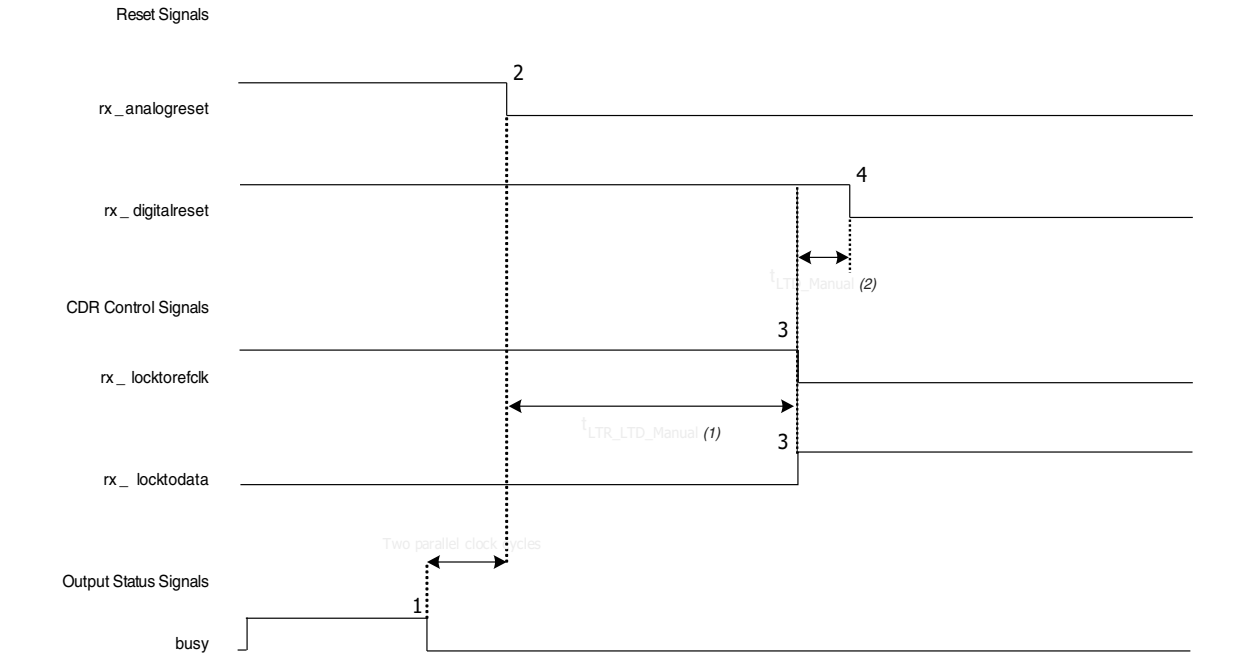


Figure 1–3 shows the lock time parameters in automatic mode.

Figure 1–3. Lock Time Parameters for Automatic Mode

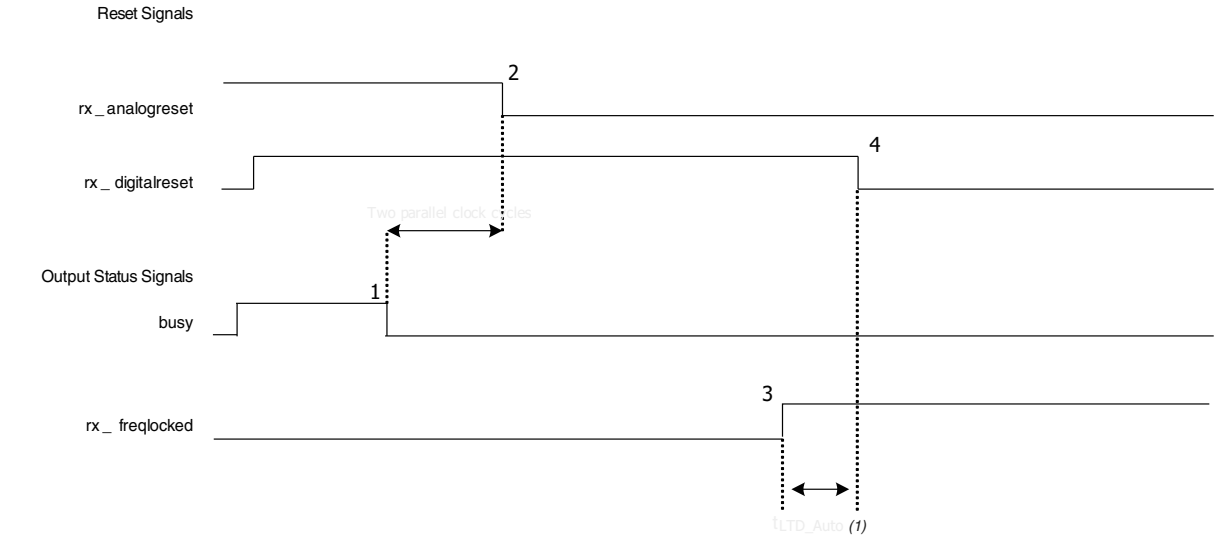


Table 1–24. Clock Tree Performance for Cyclone IV Devices *(Part 2 of 2)*

Device	Performance								Unit
	C6	C7	C8	C8L (1)	C9L (1)	I7	I8L (1)	A7	
EP4CE55	500	437.5	402	362	265	437.5	362	—	MHz
EP4CE75	500	437.5	402	362	265	437.5	362	—	MHz
EP4CE115	—	437.5	402	362	265	437.5	362	—	MHz
EP4CGX15	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX22	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX30	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX50	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX75	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX110	500	437.5	402	—	—	437.5	—	—	MHz
EP4CGX150	500	437.5	402	—	—	437.5	—	—	MHz

Note to Table 1–24:

(1) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades.

PLL Specifications

Table 1–25 lists the PLL specifications for Cyclone IV devices when operating in the commercial junction temperature range (0°C to 85°C), the industrial junction temperature range (–40°C to 100°C), the extended industrial junction temperature range (–40°C to 125°C), and the automotive junction temperature range (–40°C to 125°C). For more information about the PLL block, refer to "Glossary" on page 1–37.

Table 1–25. PLL Specifications for Cyclone IV Devices (1), (2) (Part 1 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
f_{IN} (3)	Input clock frequency (–6, –7, –8 speed grades)	5	—	472.5	MHz
	Input clock frequency (–8L speed grade)	5	—	362	MHz
	Input clock frequency (–9L speed grade)	5	—	265	MHz
f_{INPFD}	PFD input frequency	5	—	325	MHz
f_{VCO} (4)	PLL internal VCO operating range	600	—	1300	MHz
f_{INDUTY}	Input clock duty cycle	40	—	60	%
$t_{INJITTER_CCJ}$ (5)	Input clock cycle-to-cycle jitter $F_{REF} \geq 100$ MHz	—	—	0.15	UI
	$F_{REF} < 100$ MHz	—	—	±750	ps
f_{OUT_EXT} (external clock output) (3)	PLL output frequency	—	—	472.5	MHz
f_{OUT} (to global clock)	PLL output frequency (–6 speed grade)	—	—	472.5	MHz
	PLL output frequency (–7 speed grade)	—	—	450	MHz
	PLL output frequency (–8 speed grade)	—	—	402.5	MHz
	PLL output frequency (–8L speed grade)	—	—	362	MHz
	PLL output frequency (–9L speed grade)	—	—	265	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%)	45	50	55	%
t_{LOCK}	Time required to lock from end of device configuration	—	—	1	ms

Embedded Multiplier Specifications

Table 1–26 lists the embedded multiplier specifications for Cyclone IV devices.

Table 1–26. Embedded Multiplier Specifications for Cyclone IV Devices

Mode	Resources Used	Performance					Unit
	Number of Multipliers	C6	C7, I7, A7	C8	C8L, I8L	C9L	
9 × 9-bit multiplier	1	340	300	260	240	175	MHz
18 × 18-bit multiplier	1	287	250	200	185	135	MHz

Memory Block Specifications

Table 1–27 lists the M9K memory block specifications for Cyclone IV devices.

Table 1–27. Memory Block Performance Specifications for Cyclone IV Devices

Memory	Mode	Resources Used		Performance					Unit
		LEs	M9K Memory	C6	C7, I7, A7	C8	C8L, I8L	C9L	
M9K Block	FIFO 256 × 36	47	1	315	274	238	200	157	MHz
	Single-port 256 × 36	0	1	315	274	238	200	157	MHz
	Simple dual-port 256 × 36 CLK	0	1	315	274	238	200	157	MHz
	True dual port 512 × 18 single CLK	0	1	315	274	238	200	157	MHz

Configuration and JTAG Specifications

Table 1–28 lists the configuration mode specifications for Cyclone IV devices.

Table 1–28. Passive Configuration Mode Specifications for Cyclone IV Devices (1)

Programming Mode	V_{CCINT} Voltage Level (V)	DCLK f_{MAX}	Unit
Passive Serial (PS)	1.0 (3)	66	MHz
	1.2	133	MHz
Fast Passive Parallel (FPP) (2)	1.0 (3)	66	MHz
	1.2 (4)	100	MHz

Notes to Table 1–28:

(1) For more information about PS and FPP configuration timing parameters, refer to the *Configuration and Remote System Upgrades in Cyclone IV Devices* chapter.

(2) FPP configuration mode supports all Cyclone IV E devices (except for E144 package devices) and EP4CGX50, EP4CGX75, EP4CGX110, and EP4CGX150 only.

(3) V_{CCINT} = 1.0 V is only supported for Cyclone IV E 1.0 V core voltage devices.

(4) Cyclone IV E devices support 1.2 V V_{CCINT}. Cyclone IV E 1.2 V core voltage devices support 133 MHz DCLK f_{MAX} for EP4CE6, EP4CE10, EP4CE15, EP4CE22, EP4CE30, and EP4CE40 only.

For more information about the supported maximum clock rate, device and pin planning, IP implementation, and device termination, refer to *Section III: System Performance Specifications* of the *External Memory Interface Handbook*.

Table 1–37 lists the memory output clock jitter specifications for Cyclone IV devices.

Table 1–37. Memory Output Clock Jitter Specifications for Cyclone IV Devices *(1), (2)*

Parameter	Symbol	Min	Max	Unit
Clock period jitter	$t_{JIT(per)}$	–125	125	ps
Cycle-to-cycle period jitter	$t_{JIT(cc)}$	–200	200	ps
Duty cycle jitter	$t_{JIT(duty)}$	–150	150	ps

Notes to Table 1–37:

(1) Memory output clock jitter measurements are for 200 consecutive clock cycles, as specified in the JEDEC DDR2 standard.

(2) The clock jitter specification applies to memory output clock pins generated using DDIO circuits clocked by a PLL output routed on a global clock (GCLK) network.

Duty Cycle Distortion Specifications

Table 1–38 lists the worst case duty cycle distortion for Cyclone IV devices.

Table 1–38. Duty Cycle Distortion on Cyclone IV Devices I/O Pins *(1), (2), (3)*

Symbol	C6		C7, I7		C8, I8L, A7		C9L		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	45	55	45	55	%

Notes to Table 1–38:

(1) The duty cycle distortion specification applies to clock outputs from the PLLs, global clock tree, and IOE driving the dedicated and general purpose I/O pins.

(2) Cyclone IV devices meet the specified duty cycle distortion at the maximum output toggle rate for each combination of I/O standard and current strength.

(3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

OCT Calibration Timing Specification

Table 1–39 lists the duration of calibration for series OCT with calibration at device power-up for Cyclone IV devices.

Table 1–39. Timing Specification for Series OCT with Calibration at Device Power-Up for Cyclone IV Devices *(1)*

Symbol	Description	Maximum	Units
t_{OCTCAL}	Duration of series OCT with calibration at device power-up	20	µs

Note to Table 1–39:

(1) OCT calibration takes place after device configuration and before entering user mode.

Table 1–44 and Table 1–45 list the IOE programmable delay for Cyclone IV GX devices.

Table 1–44. IOE Programmable Delay on Column Pins for Cyclone IV GX Devices *(1), (2)*

Parameter	Paths Affected	Number of Settings	Min Offset	Max Offset						Unit
				Fast Corner		Slow Corner				
				C6	I7	C6	C7	C8	I7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.313	1.209	2.184	2.336	2.451	2.387	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.312	1.208	2.200	2.399	2.554	2.446	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.438	0.404	0.751	0.825	0.886	0.839	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.713	0.682	1.228	1.41	1.566	1.424	ns

Notes to Table 1–44:

(1) The incremental values for the settings are generally linear. For exact values of each setting, use the latest version of the Quartus II software.

(2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–45. IOE Programmable Delay on Row Pins for Cyclone IV GX Devices *(1), (2)*

Parameter	Paths Affected	Number of Settings	Min Offset	Max Offset						Unit
				Fast Corner		Slow Corner				
				C6	I7	C6	C7	C8	I7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.210	2.209	2.398	2.526	2.443	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.313	1.208	2.205	2.406	2.563	2.450	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.461	0.421	0.789	0.869	0.933	0.884	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.712	0.682	1.225	1.407	1.562	1.421	ns

Notes to Table 1–45:

(1) The incremental values for the settings are generally linear. For exact values of each setting, use the latest version of Quartus II software.

(2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software

Table 1–46. Glossary (Part 2 of 5)

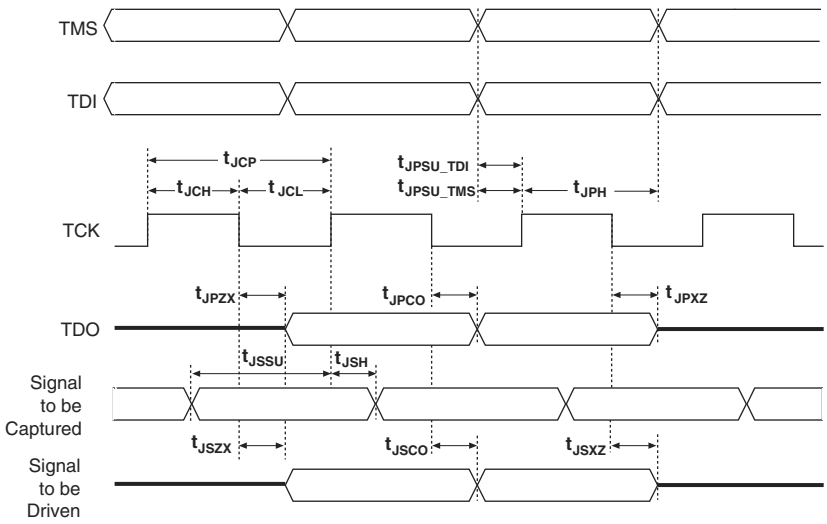
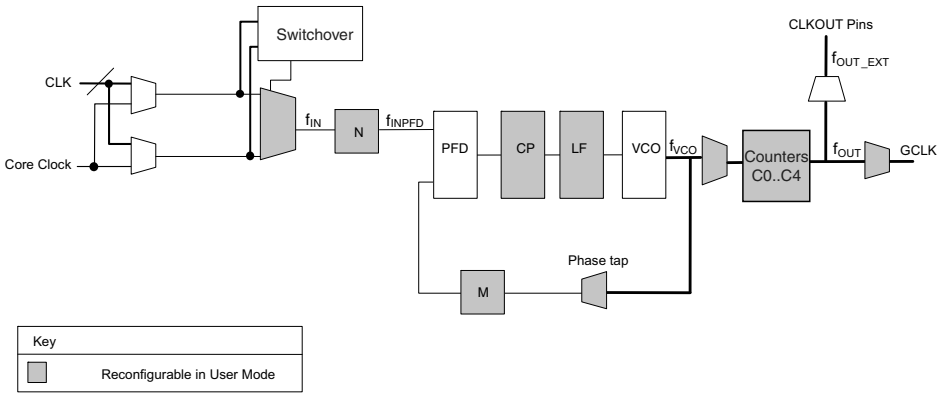
Letter	Term	Definitions
J	JTAG Waveform	
K	—	—
L	—	—
M	—	—
N	—	—
O	—	—
P	PLL Block	The following highlights the PLL specification parameters: 
Q	—	—

Table 1–46. Glossary (Part 3 of 5)

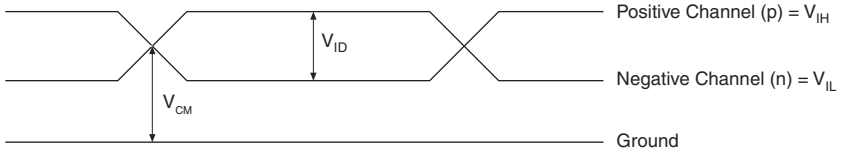
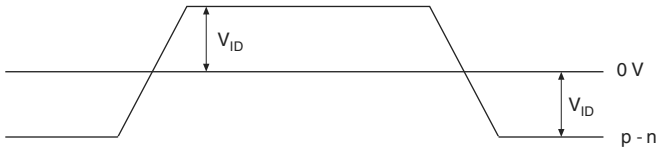
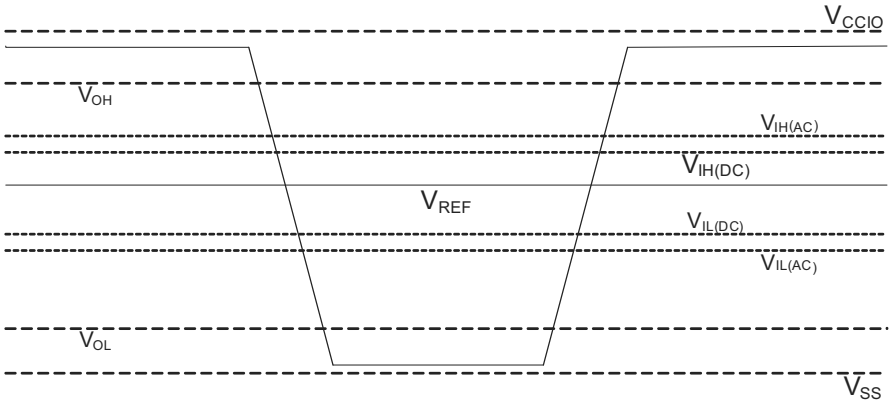
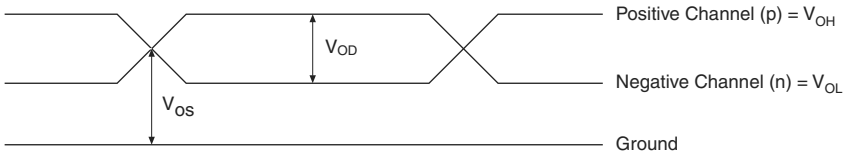
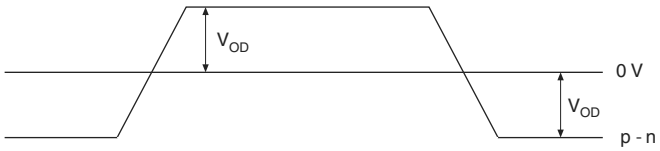
Letter	Term	Definitions
R	R_L	Receiver differential input discrete resistor (external to Cyclone IV devices).
	Receiver Input Waveform	Receiver input waveform for LVDS and LVPECL differential standards: **Single-Ended Waveform**  **Differential Waveform (Mathematical Function of Positive & Negative Channel)** 
	Receiver input skew margin (RSKM)	High-speed I/O block: The total margin left after accounting for the sampling window and TCCS. RSKM = (TUI – SW – TCCS) / 2.
S	Single-ended voltage-referenced I/O Standard	 The JEDEC standard for SSTI and HSTL I/O standards defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input crosses the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform *ringing*.
	SW (Sampling Window)	High-speed I/O block: The period of time during which the data must be valid to capture it correctly. The setup and hold times determine the ideal strobe position in the sampling window.

Table 1–46. Glossary (Part 4 of 5)

Letter	Term	Definitions
T	t_C	High-speed receiver and transmitter input and output clock period.
	Channel-to-channel-skew (TCCS)	High-speed I/O block: The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.
	t_{cin}	Delay from the clock pad to the I/O input register.
	t_{CO}	Delay from the clock pad to the I/O output.
	t_{cout}	Delay from the clock pad to the I/O output register.
	t_{DUTY}	High-speed I/O block: Duty cycle on high-speed transmitter output clock.
	t_{FALL}	Signal high-to-low transition time (80–20%).
	t_H	Input register hold time.
	Timing Unit Interval (TUI)	High-speed I/O block: The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = 1/(Receiver Input Clock Frequency Multiplication Factor) = t_C/w).
	$t_{INJITTER}$	Period jitter on the PLL clock input.
	$t_{OUTJITTER_DEDCLK}$	Period jitter on the dedicated clock output driven by a PLL.
	$t_{OUTJITTER_IO}$	Period jitter on the general purpose I/O driven by a PLL.
	t_{plicin}	Delay from the PLL inclk pad to the I/O input register.
	$t_{plicout}$	Delay from the PLL inclk pad to the I/O output register.
	Transmitter Output Waveform	Transmitter output waveforms for the LVDS, mini-LVDS, PPDS and RSDS Differential I/O Standards: **Single-Ended Waveform**  **Differential Waveform (Mathematical Function of Positive & Negative Channel)** 
	t_{RISE}	Signal low-to-high transition time (20–80%).
	t_{SU}	Input register setup time.
U	—	—